

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Complete if Known

Application Number	10/722,806
Filing Date	November 26, 2003
First Named Inventor	Osamah M. El Rifai
Art Unit	2829
Examiner Name	Not Yet Assigned
Attorney Docket Number	MIT-135PUS

Sheet	1	of	2
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Sheet	12	of	2	Attorney Docket Number	MIT-135PUS

OTHER PRIOR ART—NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SYE		International Search Report for Application No. PCT/US2004/034390 dated April 12, 2005.	
SYE		SCHAFFER, T.E., ET AL., "Characterization and Optimization of the Detection Sensitivity of an Atomic Force Microscope for Small Cantilevers", Journal of Applied Physics AIP USA, vol. 84, no. 9, November 1, 1998, pages 4661-4666.	
SYE		KINDT, JOHANNES H. ET AL., Atomic Force Microscope Detector Drift Compensation by Correlation of Similar Traces Acquired at Different Setpoints", Review of Scientific Instruments, American Institute of Physics, UA, vol. 73, no. 6, June 2002, pages 2305-2307.	
SYE		AUMOND, B.D. ET AL., "High Precision Metrology by Means of a Novel Stereo Imaging Technique Based on atomic Force Microscopy", Proceeding of the SPIE - The International Society for Optical Engineering SPIE - INT. SOC. OPT. ENG USA, vol., 4344, February 26, 2001, pages 46-57.	
SYE		PINGALI, G.S. ET AL., "Restoration of Scanning Probe Microscope Images", Applications of Computer Vision, Proceeding, 1992, IEEE Workshop on Palm Springs, CA, USA, November 30 - December 2, 1992, Los Alamitos, CA, USA, IEEE COMPUT. SOC, US, November 30, 1992, pages 282-289.	

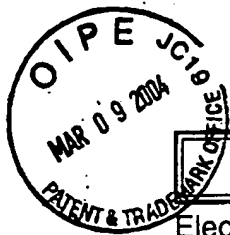
Examiner Signature	<i>Sue Ellis</i>	Date Considered	18 JUL 05
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Title of Invention	HEIGHT CALIBRATION OF SCANNING PROBE MICROSCOPE ACTUATORS																																																																																																																						
<p>Application Number: 10/722806 </p> <p>Confirmation Number: 8192</p> <p>First Named Applicant: Osamah El Rifai</p> <p>Attorney Docket Number: MIT-135PUS</p> <p>Art Unit: 2829</p> <p>Search string: (5200617 or 5920067 or 6661004 or 5051646 or 5641897 or 5825670 or 6016684 or 5665905 or 5664512 or 5557156 or 5463897 or 5155359 or RE37299 or 5877497 or 5801381 or 5773824 or 6244103 or 5898106 or 5804708 or 5497656 or 6340858 or 5568003 or 5469734 or 5384507 or 6410907 or 6357285 or RE37404 or 5418363 or 5306919 or 5198715 or 5801390 or 5077473 or 5066858 or RE37560).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td>SYE</td><td>1</td><td>5200617</td><td>1993-04-06</td><td>Hayes et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>2</td><td>5920067</td><td>1999-07-06</td><td>Cresswell et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>3</td><td>6661004</td><td>2003-12-09</td><td>Aumond et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>4</td><td>5051646</td><td>1991-09-24</td><td>Elings et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>5</td><td>5641897</td><td>1997-06-24</td><td>Schuman</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>6</td><td>5825670</td><td>1998-10-20</td><td>Chernoff et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>7</td><td>6016684</td><td>2000-01-25</td><td>Scheer et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>8</td><td>5665905</td><td>1997-09-09</td><td>Bartha et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>9</td><td>5664512</td><td>1997-07-01</td><td>Chernoff et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>10</td><td>5557156</td><td>1996-09-17</td><td>Elings</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>11</td><td>5463897</td><td>1995-11-07</td><td>Prater et al.</td><td></td><td></td><td></td></tr><tr><td>SYE</td><td>12</td><td>5155359</td><td>1992-10-13</td><td>Monahan</td><td></td><td></td><td></td></tr><tr><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td></tr></tbody></table>								init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass	SYE	1	5200617	1993-04-06	Hayes et al.				SYE	2	5920067	1999-07-06	Cresswell et al.				SYE	3	6661004	2003-12-09	Aumond et al.				SYE	4	5051646	1991-09-24	Elings et al.				SYE	5	5641897	1997-06-24	Schuman				SYE	6	5825670	1998-10-20	Chernoff et al.				SYE	7	6016684	2000-01-25	Scheer et al.				SYE	8	5665905	1997-09-09	Bartha et al.				SYE	9	5664512	1997-07-01	Chernoff et al.				SYE	10	5557156	1996-09-17	Elings				SYE	11	5463897	1995-11-07	Prater et al.				SYE	12	5155359	1992-10-13	Monahan											
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SYE	19	5804708	1998-09-08	Yamanaka et al.
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SYE	21	6340858	2002-01-22	Jaenker
SYE	22	5568003	1996-10-22	Deck
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SYE	24	5384507	1995-01-24	Takada et al.
SYE	25	6410907	2002-06-25	Cleveland et al.
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SYE	28	5418363	1995-05-23	Elings et al.
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SYE	33	5066858	1991-11-19	Elings et al.
SYE	34	RE37560	2002-02-26	Elings

Signature

Examiner Name	Date
<i>Suzanne Ellis</i>	18 JUL 05